

Specification MAP/CV57/Issue 5 Dated 30.4.48 To be read in conjunction with K1001, ignoring clauses:- 5.2, 5.3, 5.8, 7.2.	<table border="1"> <tr> <th colspan="2"><u>SECURITY</u></th></tr> <tr> <td><u>Specification</u> RESTRICTED Unclass</td><td><u>Valve</u> UNCLASSIFIED</td></tr> </table>	<u>SECURITY</u>		<u>Specification</u> RESTRICTED Unclass	<u>Valve</u> UNCLASSIFIED
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<u>Specification</u> RESTRICTED Unclass	<u>Valve</u> UNCLASSIFIED				

—————> Indicates a change

<u>TYPE OF VALVE</u> - Tetrode			<u>MARKING</u> See K1001/4		
<u>CATHODE</u> - Indirectly heated			<u>BASE</u> T4 See K1001/AIV/D7		
<u>ENVELOPE</u> - Glass-unmetallised					
<u>RATING</u>		<u>Note</u>	<u>TOP CAP</u> See K1001/AI/D5.1		
			<u>DIMENSIONS</u> See K1001/AI/D1.		
<u>CAPACITANCES (pF)</u>			<u>Dimension</u>		
			<u>Pin.</u>		
			<u>Max.</u>		
			</		

To be performed in addition to those applicable in K1001.

	Test Conditions						Test	Limits		No. Tested	Note
	Vh	Vg1	Vg2	Va	Ig2	Ia		Min.	Max.		
a	Between 12V. and 15V.	-	Strapped. Applied voltage raised slowly to 3.5kV. and maintained till flashing ceases.		A trace		<u>SCREEN HOT FLASH PROCESS</u> Applied anode and screen voltage to be maintained at 3.5kV. for a period of one minute without further flashing.			100%	1
b	ditto	Strapped	Raised slowly to 18kV and maintained till flashing ceases.		-	A trace	<u>ANODE HOT FLASH PROCESS</u> Applied anode voltage to be maintained at 18kV. for a period of one minute without further flashing.			100%	1
c	12.6	0	0	0	0	0	Ih (A)	1.55	1.95	100%	
d	12.6	-	Strapped. 200V. applied. Maintained for 30secs.		Ia + Ig2 = 75mA.		Ig (μA)	-	20	100%	
e	12.6	-	Strapped. 200V. applied.		Ia + Ig2 = 75mA.		Vg1 (V)	-30	-45	100%	
f	12.6	-	See Note 2.		-	10μA	Vg1 (V)	-	-25	100%	2
g	5.25 A.C. or D.C.	0	Strapped. 300V. applied.		-	-	Ic (mA)	15	-	100%	
h	See K1001/AIII						<u>CAPACITANCES</u> (pF)				
							1. Cae	6.9	11.1	1%(1)	
							2. Cge	15.75	26.25	1%(1)	

NOTES

- 1:- Tests (a) and (b) form part of the processing of the valve, and having been met during manufacture they shall not be repeated for acceptance testing. For these hot flash tests, the applied voltage shall be supplied through a circuit as in Fig.1, page 3.
2. For test (f), the anode and screen grid voltages shall be derived from the network as in Fig.2, page 3.

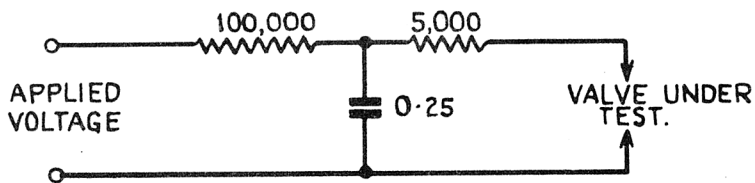


FIG. 1.

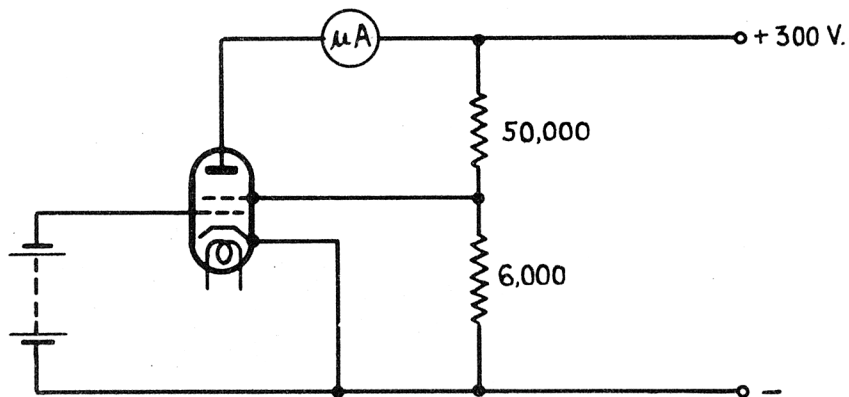


FIG. 2.

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